

Role of thermal activation in the spin-orbit torque switching of antiferromagnets

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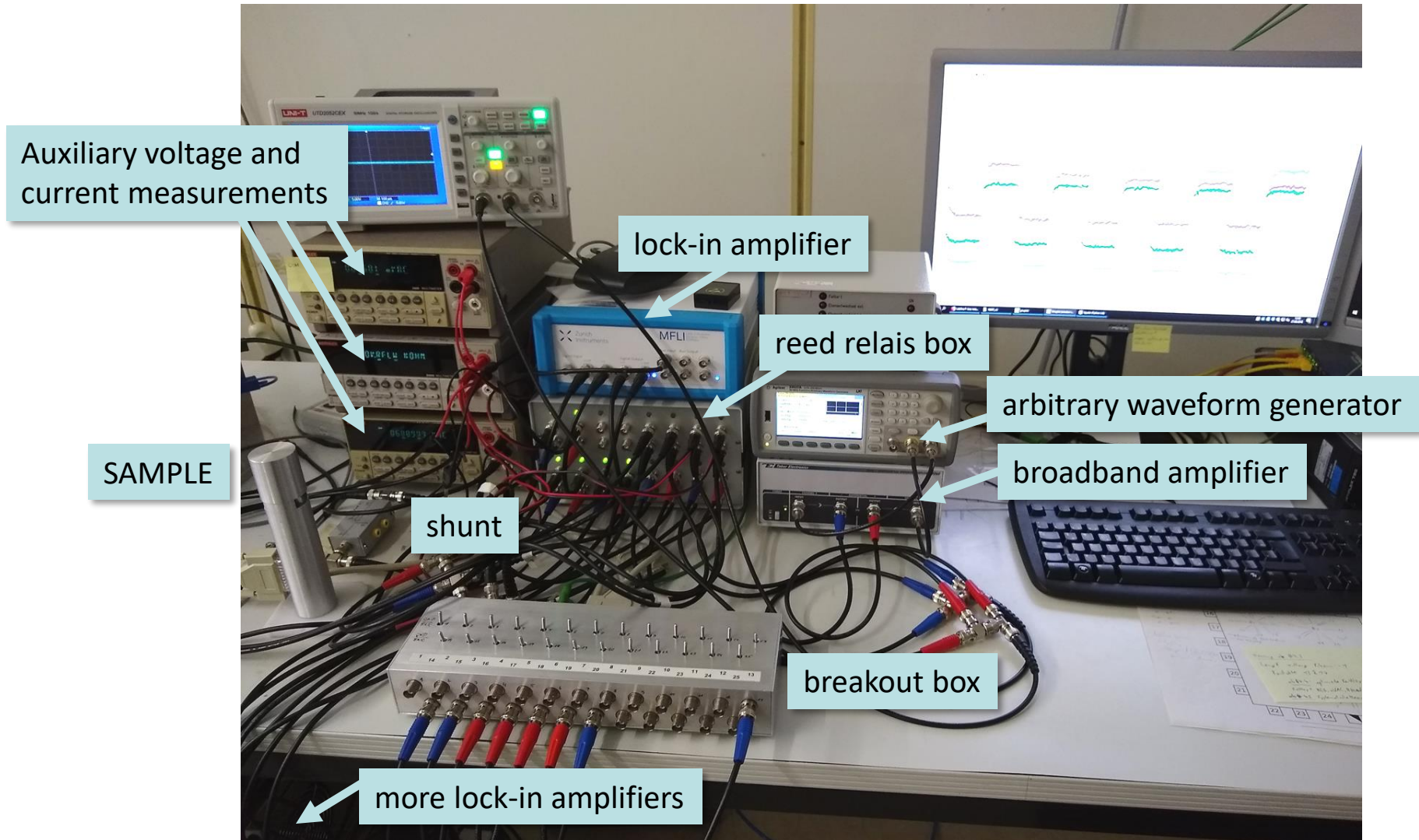
Center for Spinelectronic Materials and Devices, Bielefeld University

Outline

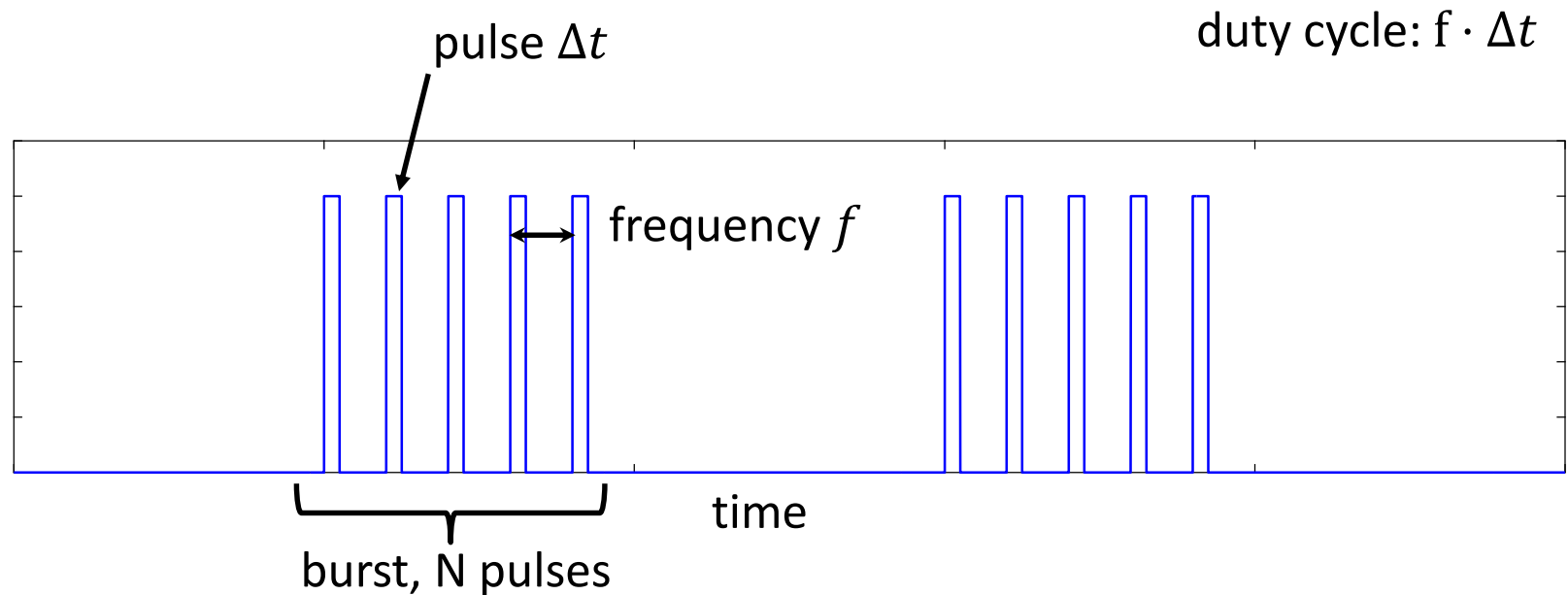
1. Thermal activation in the Néel-order switching of Mn_2Au
2. Néel-order switching in magnetron-sputtered CuMnAs films
3. Electrical switching of the Néel order in MnN with the spin Hall effect of Pt
4. Ohmic contributions to the electrical read-out

Thermal activation in the Néel-order switching of Mn_2Au

Electrical observation of the Néel-order switching

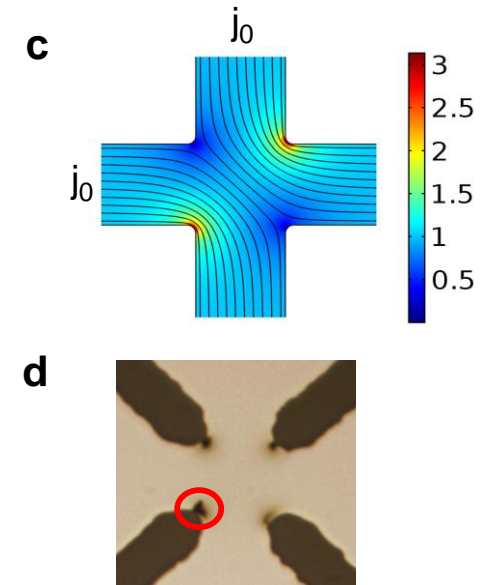
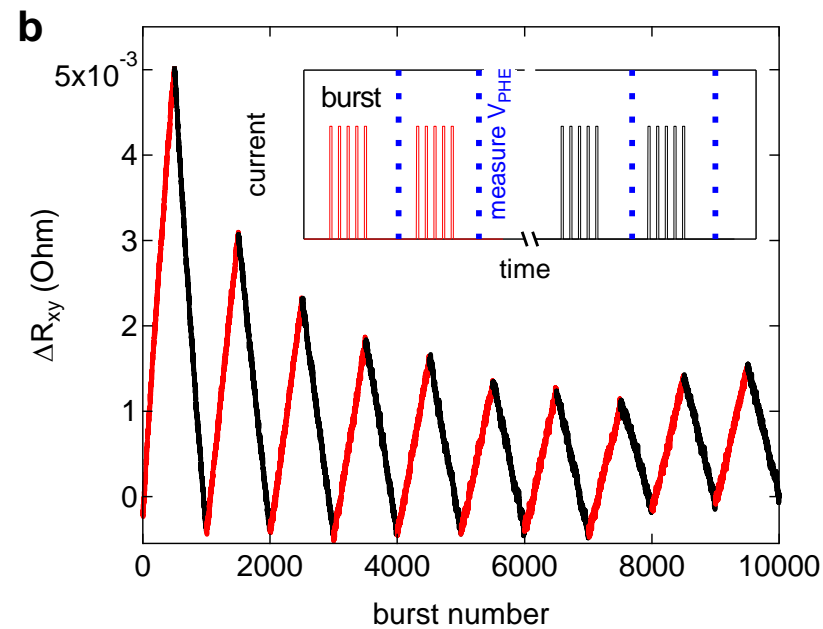
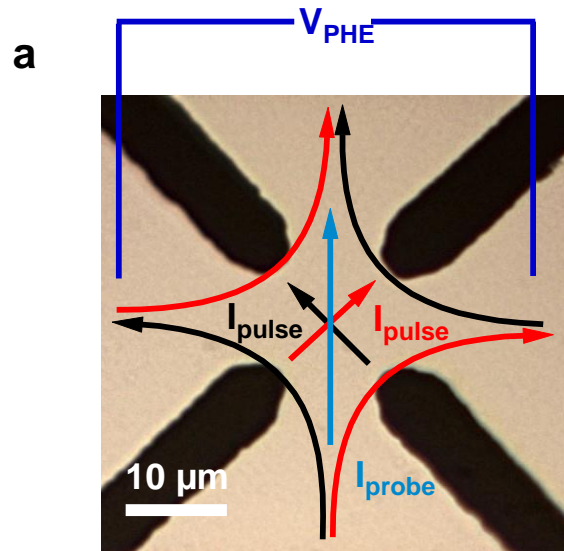


Pulses and bursts

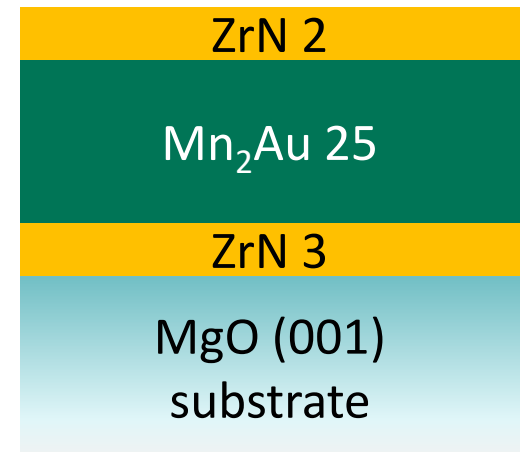


- Long single pulse heats the film
- Chop the single pulse into N shorter pulses
- Keep the total charge per burst constant, i.e. $Nj\Delta t = const.$

Electrical switching of Mn₂Au



Electrical switching of Mn₂Au is observed!



Thermal activation model - Part I

Idea: Uncoupled grains, coherent switching.

Energy:

$$E/V_g = K_{4\parallel} \sin^2 2\varphi - \mathbf{L} \cdot \mathbf{B}_{\text{eff}}/V_{\text{cell}}$$

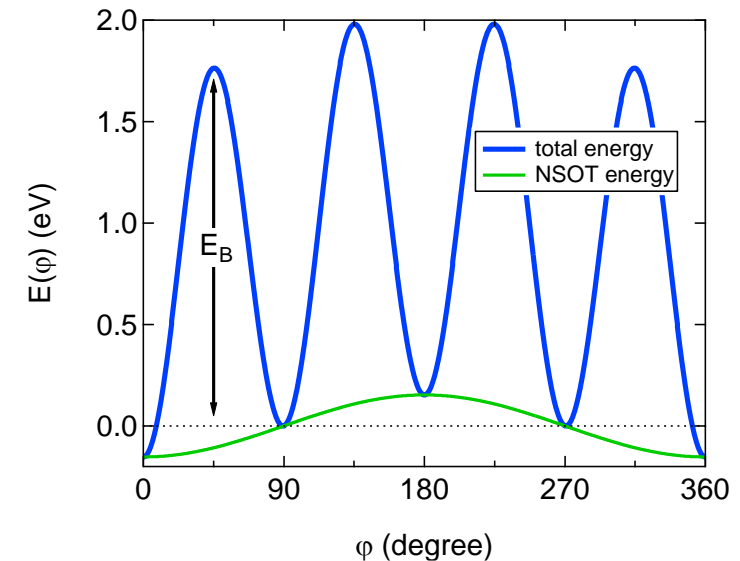
Energy barrier:

$$E_B = \min_{CW,CCW} \left(\max_{[\varphi_i, \varphi_f]} [K_{4\parallel} \sin^2 2\varphi - (\mathbf{L} \cdot \mathbf{B}_{\text{eff}})/V_{\text{cell}}] - E(\varphi_i) \right)$$

Effective field:

$$\mathbf{B}_{\text{eff}} = (\mathbf{j} \times \mathbf{z}) \cdot \chi$$

$K_{4\parallel}$: anisotropy energy density
 V_g : grain volume
 V_{cell} : unit cell volume
 χ : spin-orbit torque efficiency



Thermal activation model - Part II

Switching rate (Néel-Arrhenius):

$$\frac{1}{\tau} = f_0 e^{-\frac{E_B}{k_B T}}$$

Switching probability:

$$P_{SW}(\Delta t) = 1 - e^{-\Delta t/\tau}$$

Film temperature:

$$T(t, \Delta t) = T_0 + \frac{2whj^2}{\pi\kappa_S\sigma} \left(\operatorname{arcsinh} \left(\frac{2\sqrt{\kappa_S t / \rho_S C_S}}{\alpha w} \right) + \Theta(t - \Delta t) \operatorname{arcsinh} \left(\frac{2\sqrt{\kappa_S (t - \Delta t) / \rho_S C_S}}{\alpha w} \right) \right)$$

f_0 : attempt rate

Δt : pulse width

T_0 : base temperature

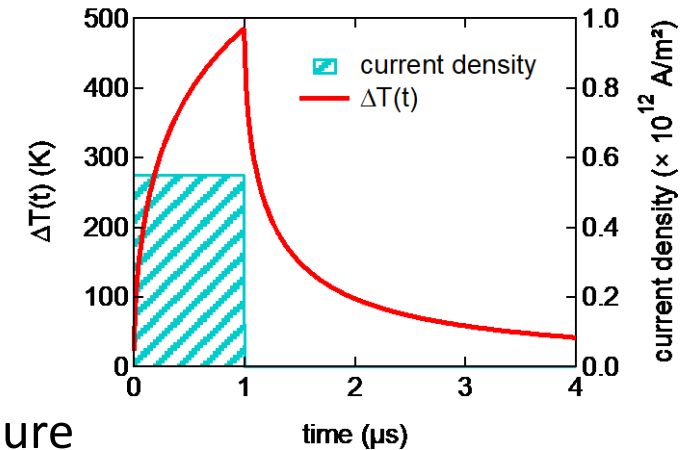
d : film thickness

w : current channel width

σ : electrical conductivity

ρ_S : density of the substrate

C_S, κ_S : thermal parameters of the substrate



Model parameters and PHE calculation

K = fitting parameter

$$V_g = \frac{\pi D^2}{4} h, \quad D = 22\text{nm}, \quad d = 25\text{nm}$$

$$V_{\text{cell}} = 4.75 \times 10^{-29} \text{m}^3$$

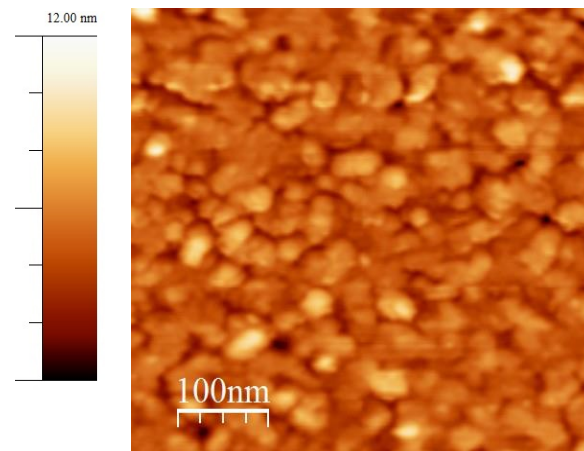
$$|\mathbf{L}| = 2 \times 4\mu_B$$

$$\chi = 0.2\text{mT}/(10^{11}\text{A}/\text{m}^2)$$

$$f_0 = 10^{12}\text{s}^{-1}$$

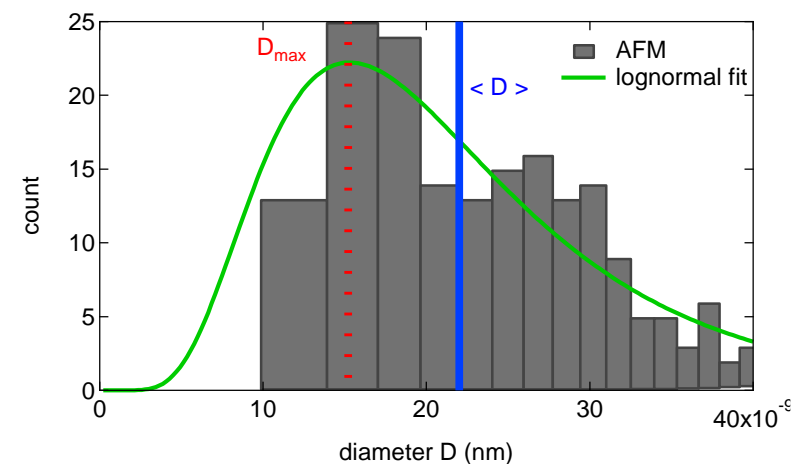
$$w \approx 12\mu\text{m}$$

$$\sigma = (73\mu\Omega\text{cm})^{-1}$$

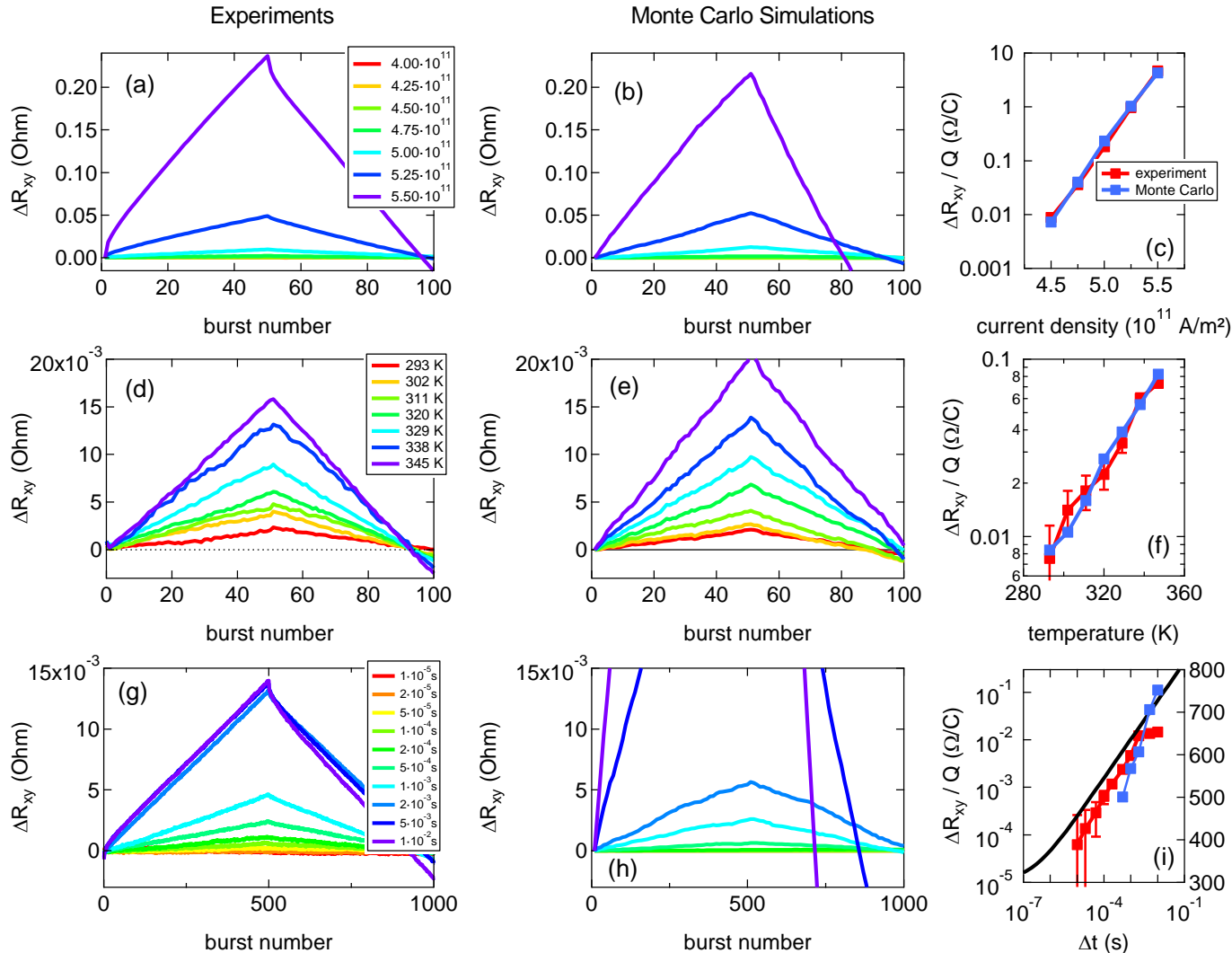


$$\Delta R_{xy} = A \langle \sin 2\varphi \rangle$$

$$A \approx 1\Omega$$



Experiment vs. theory



Anisotropy energy per grain:
 $K_{4\parallel} V_g \approx 1.5 \text{ eV}$

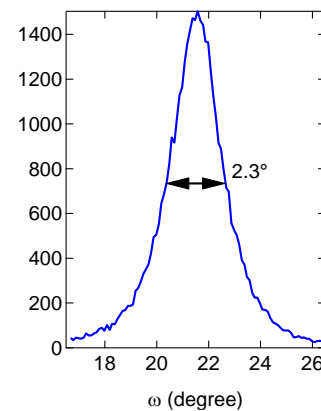
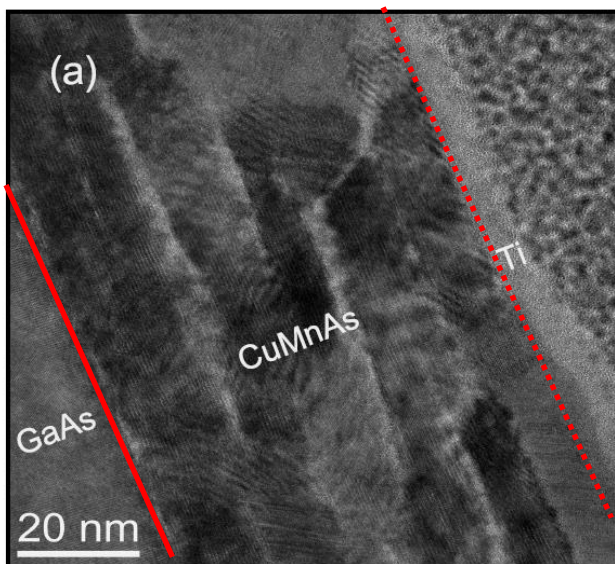
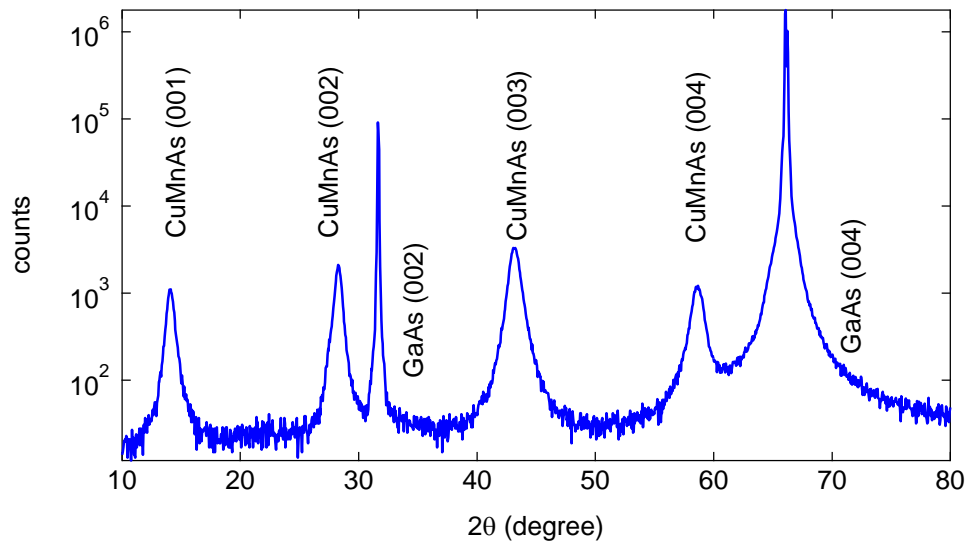
Anisotropy energy density:
 $K_{4\parallel} V_g \approx 7.5 \mu\text{eV/f.u.}$

Thermal stability factor at RT:

$$\Delta = \frac{KV_g}{k_B T} \approx 60$$

Néel-order switching in magnetron-sputtered CuMnAs films

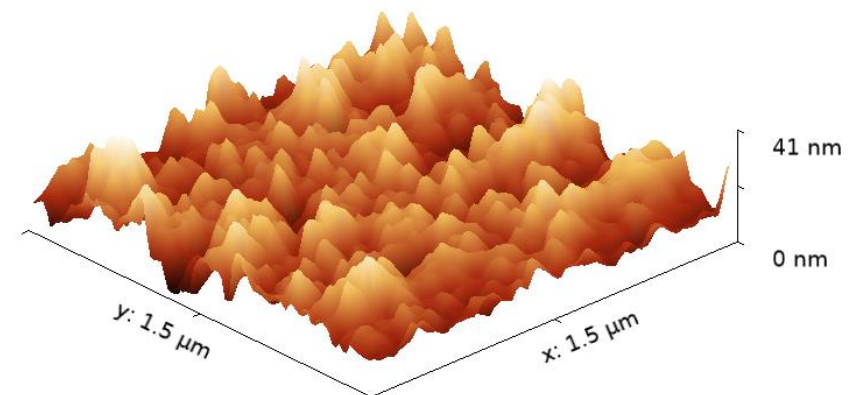
Magnetron-sputtered CuMnAs



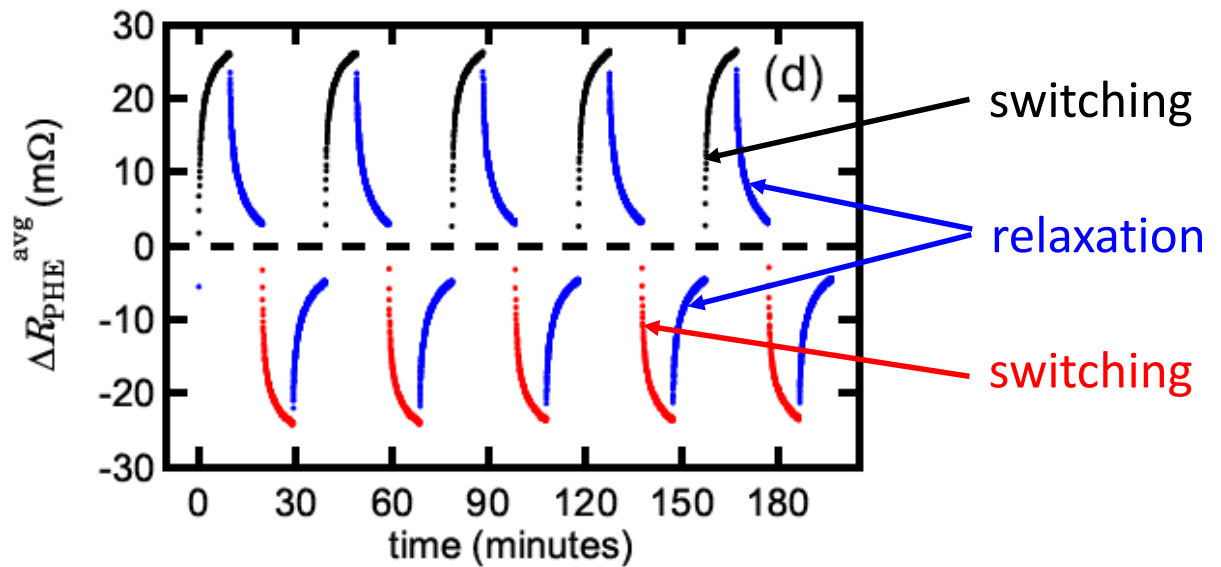
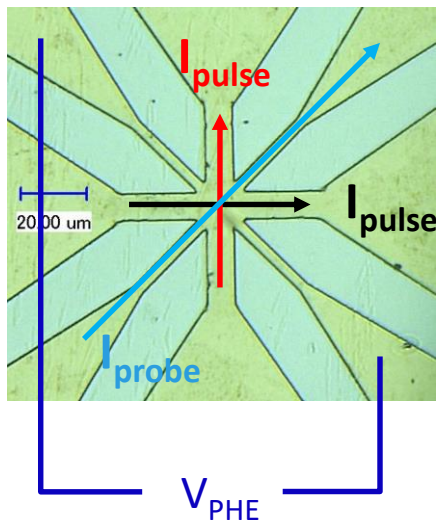
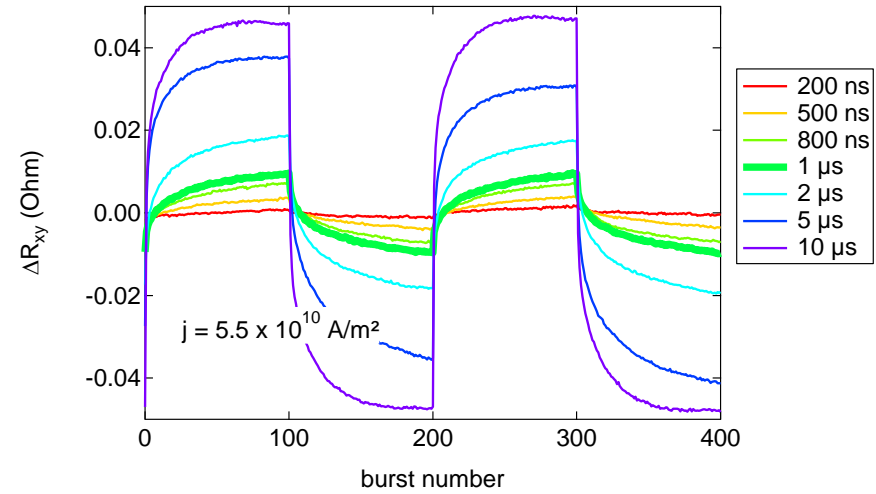
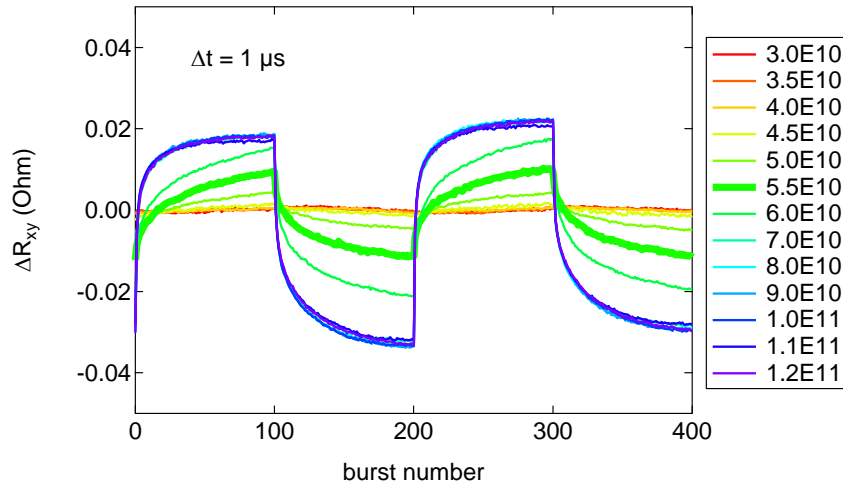
- Growth of CuMnAs from alloy target
- Substrate temperature: 410°C

GaAs (001) / CuMnAs 100 nm / Ti 3nm

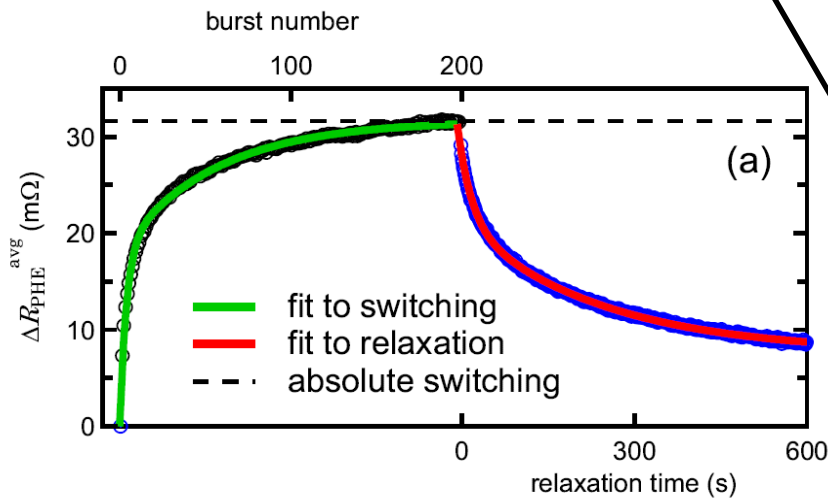
- Oriented growth of tetragonal CuMnAs with preferred (001) direction
- Perpendicular grain size \approx 10nm
- Large surface roughness



Electrical switching of CuMnAs



Parameter extraction



Solution of our model equations in linear response:

$$|\Delta R_{\text{PHE}}^{\text{burst}}| \approx \frac{Q A f_0}{j \omega h} \exp\left(\frac{L \chi V_g j}{\sqrt{2} k_B T V_c} - \frac{E_B}{k_B T}\right)$$

Exact solution for decay (relaxation):

$$R_{\text{PHE}}(t) = R_{\text{PHE}}(t = 0) \exp\left(-\frac{t}{\tau}\right)$$

$$E_B^i = \ln(f_0 \tau_i) k_B T_s$$

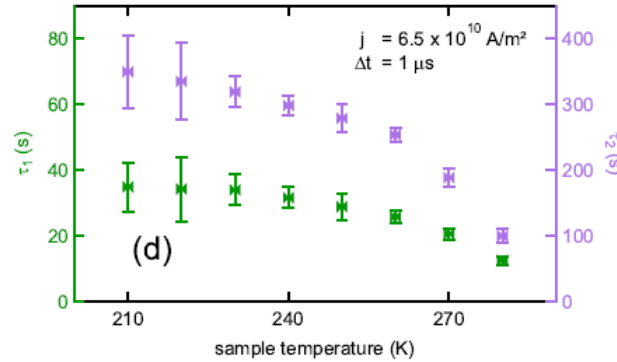
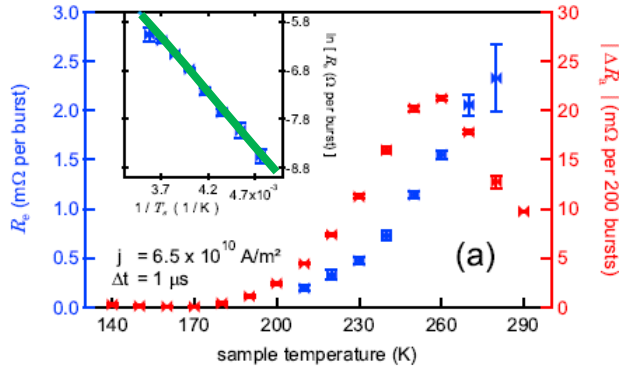
Empirical fit of pulsing- and relaxation-phases

$$R_p(b) = R_{0,p} + c_1 \exp\left(-\frac{b}{\mu_1}\right) + c_2 \exp\left(-\frac{b}{\mu_2}\right)$$

$$R_r(t) = R_{0,r} + d_1 \exp\left(-\frac{t}{\tau_1}\right) + d_2 \exp\left(-\frac{t}{\tau_2}\right)$$

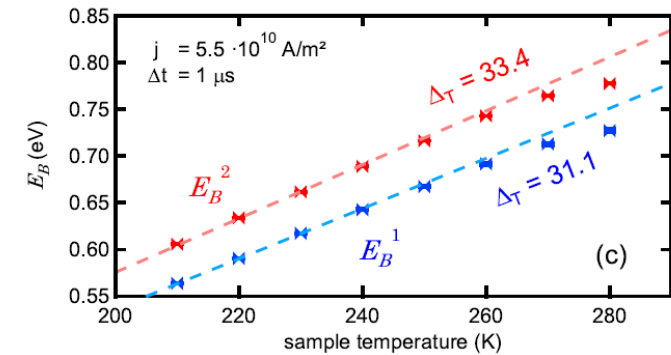
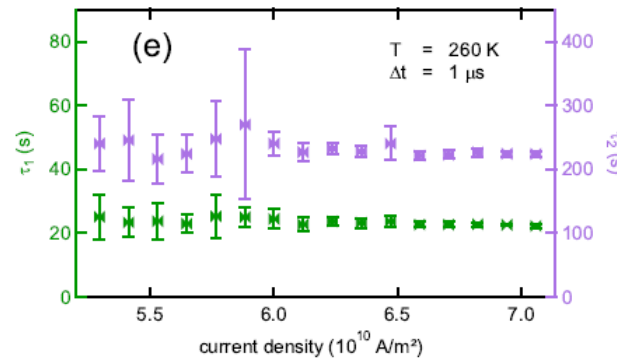
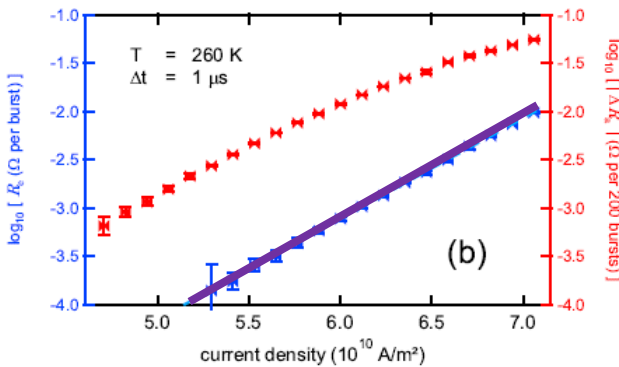
$$R_e = \left| \frac{dR_p(b)}{db} \right|_{b=0}$$

Dependences on $T, j, \Delta t$

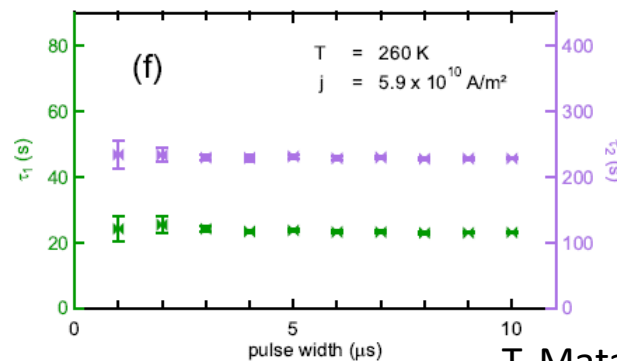
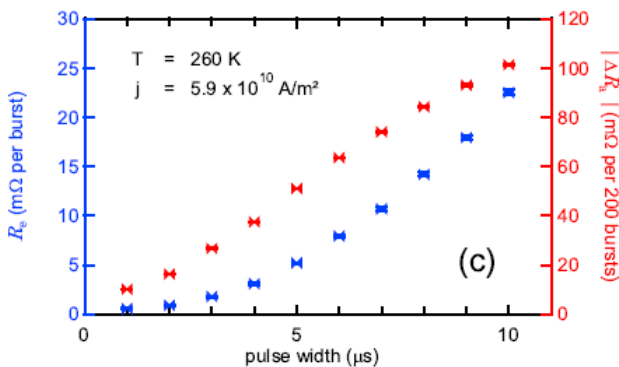


$$\ln R_e = k_1 + \frac{k_2}{T}$$

$$\ln R_e = m_1 j + m_2 + \ln j$$

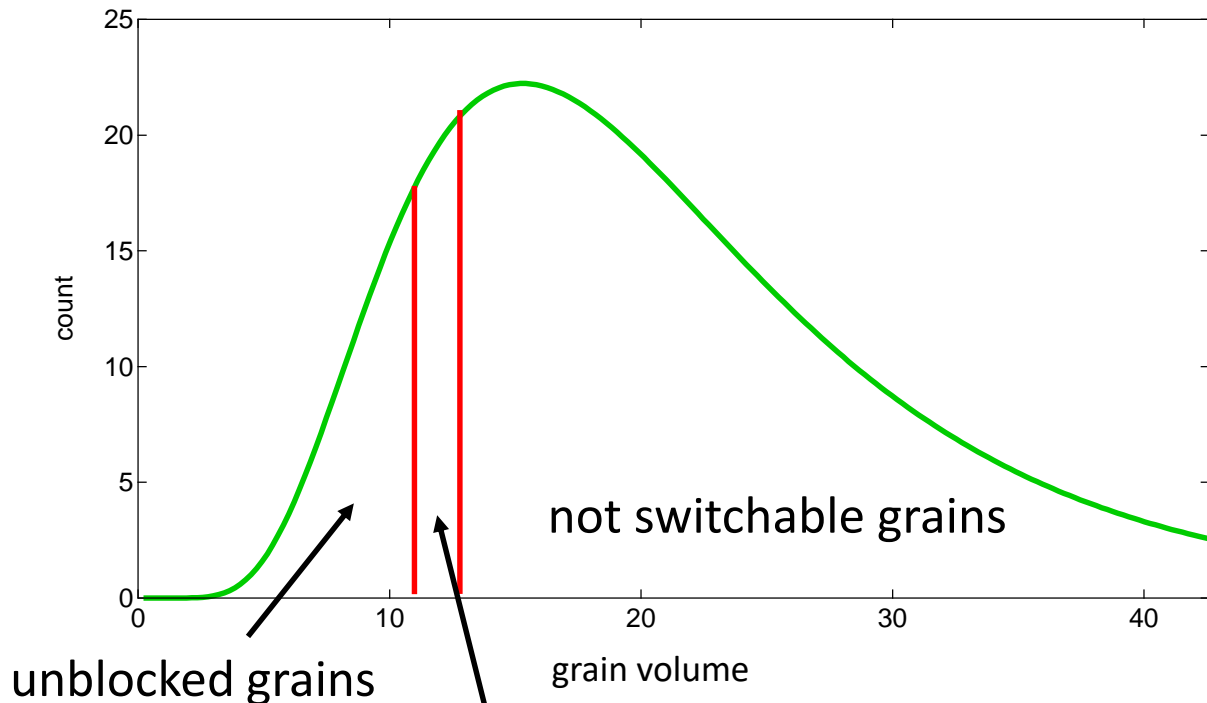


$$E_B^i = \ln(f_0 \tau_i) k_B T_s$$

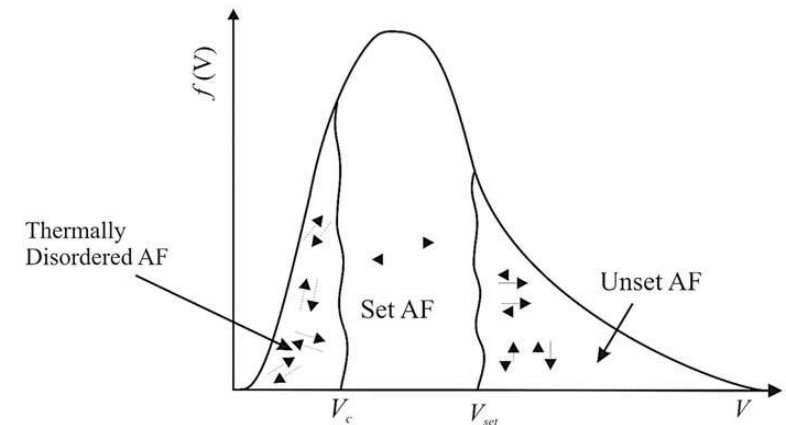


We switch grains with lower barrier at lower temperature, because χ is constant!

Size matters: grain size distribution and (un-)blocking



“active part” of the distribution, changes with T_0



Inspired by **exchange bias** physics!

K. O’Grady et al.

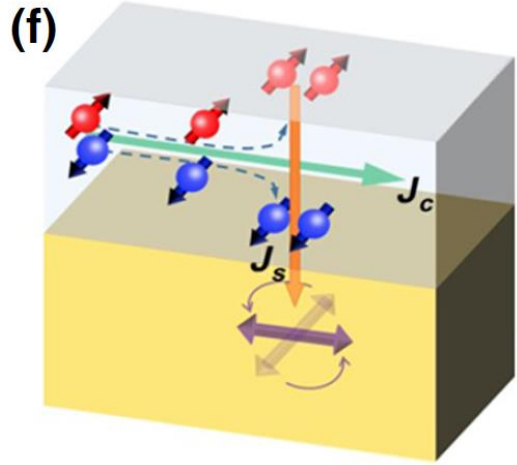
J. Magn. Mater. **322**, 883 (2010)

Joule heating makes blocked grains switchable!

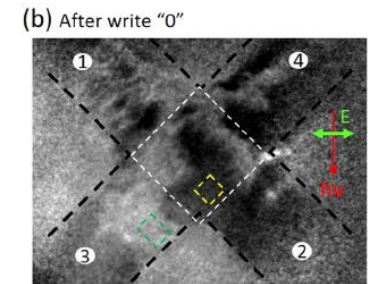
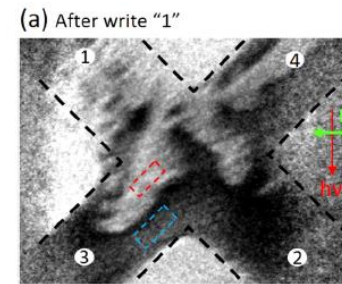
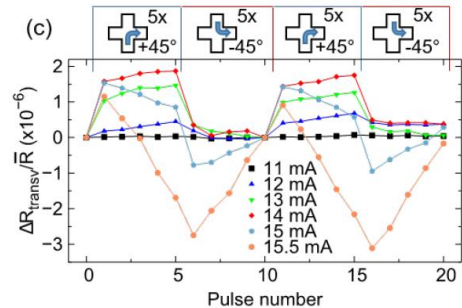
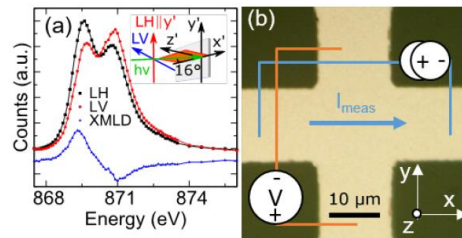
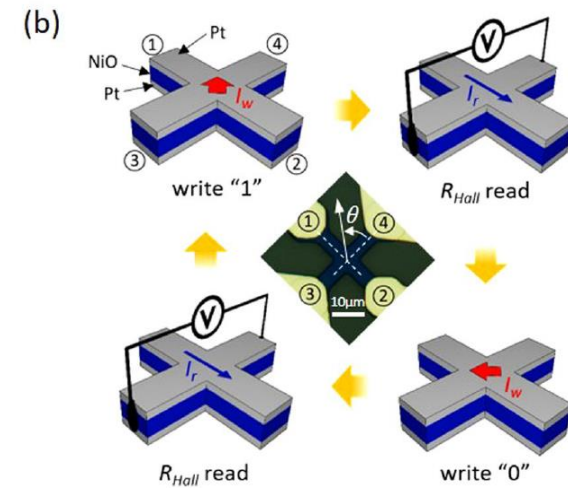
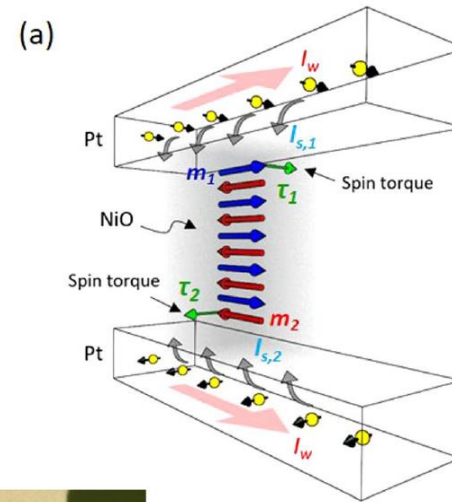
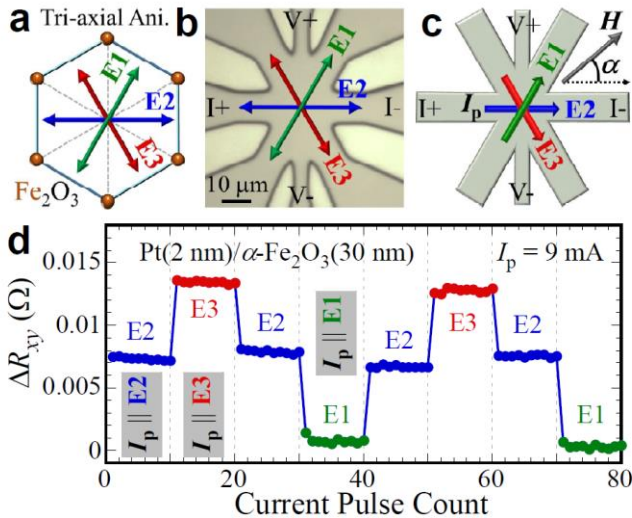
The switching must be thermally assisted! Otherwise, long-term retention of written state is impossible.

Electrical switching of the Néel order in MnN with the spin Hall effect of Pt

Switching antiferromagnets with the spin Hall effect

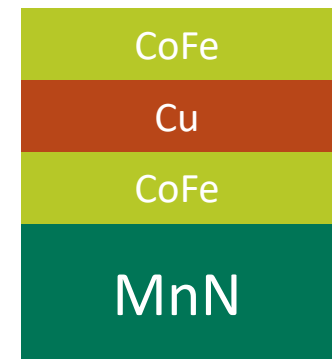
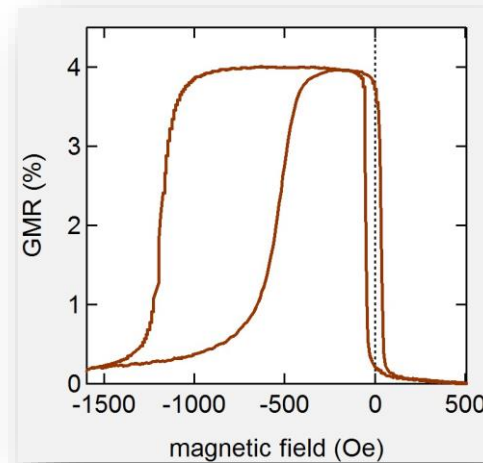
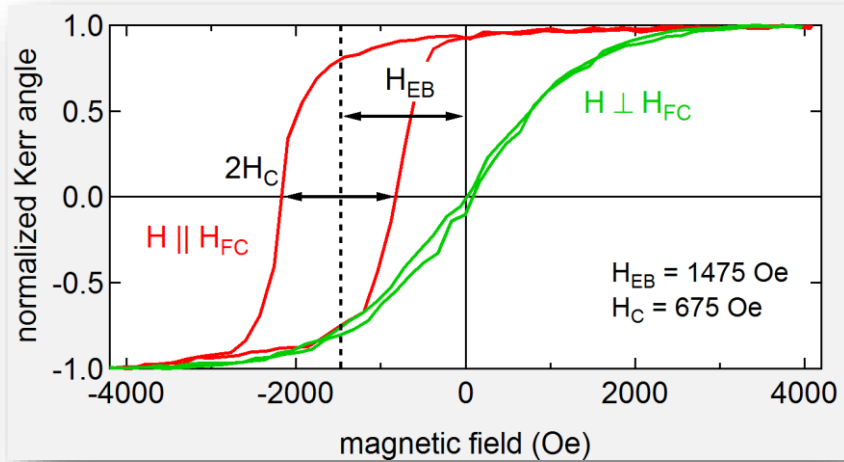
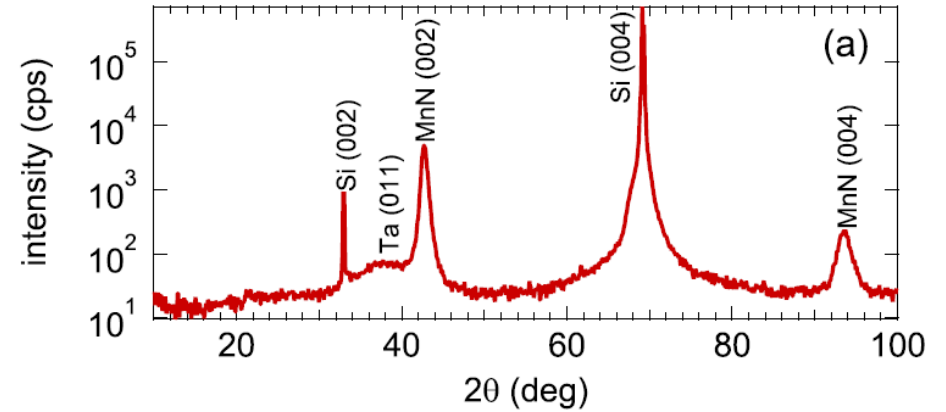
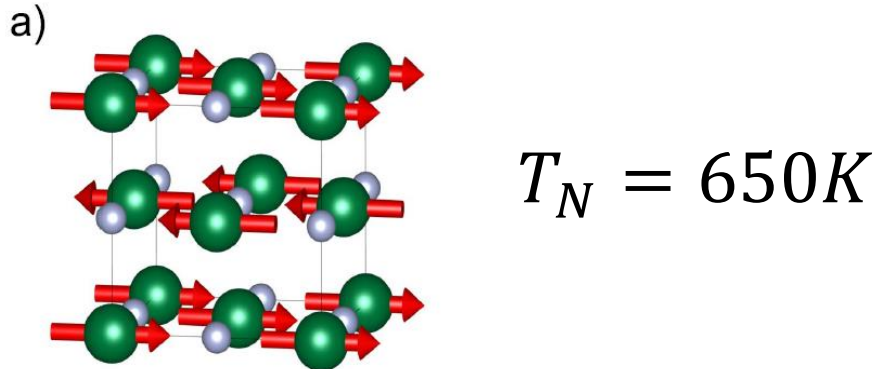


Spin current due to spin Hall effect favors $n \parallel j_c$



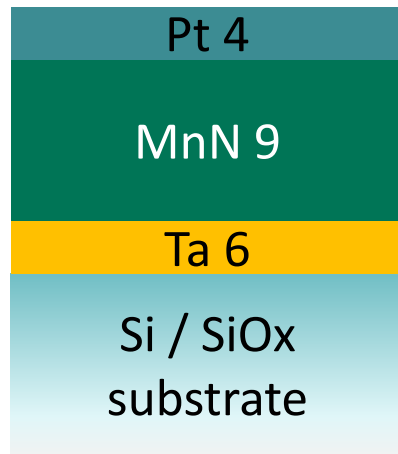
X. F. Zhou et al., Phys. Rev. Appl. **11**, 054030 (2019)
 Baldrati et al., arXiv: 1810.11326v2
 T. Moriyama et al., Sci. Rep. **8**, 14167 (2018)
 Y. Cheng et al., arXiv:1906.04694

The antiferromagnet MnN



Ta 10 / MnN 32 / CoFe 1.6 / Ta 2

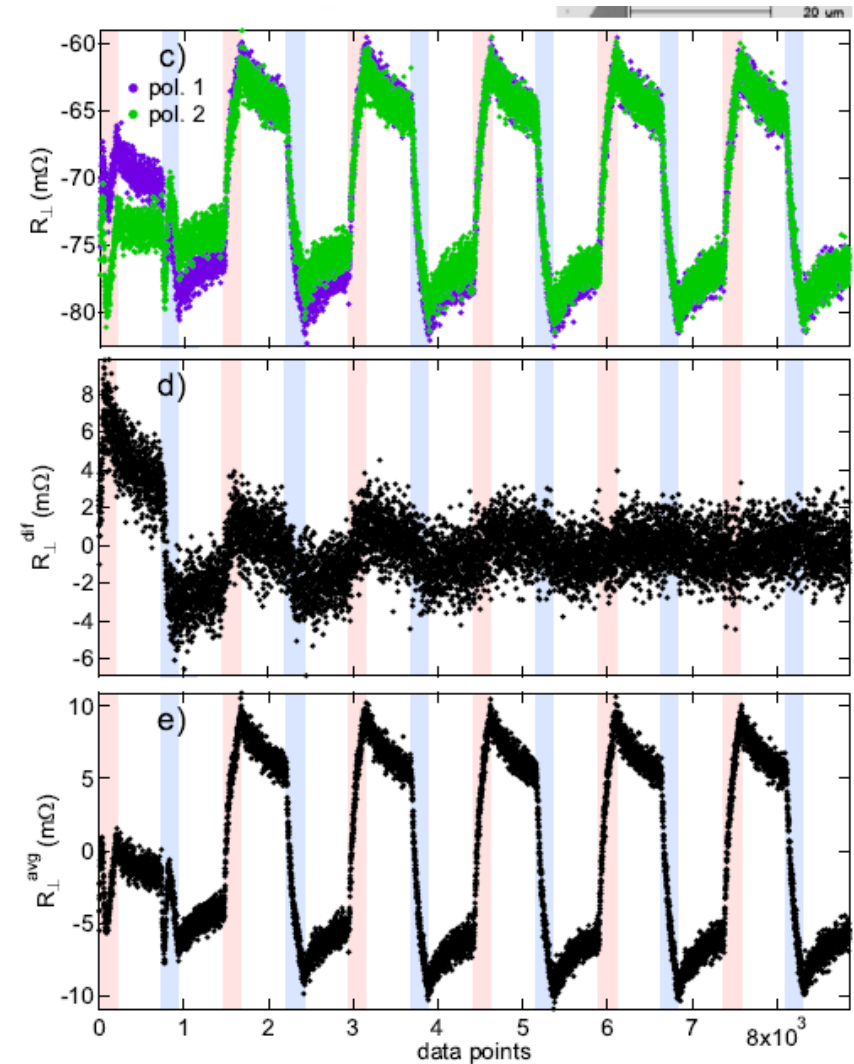
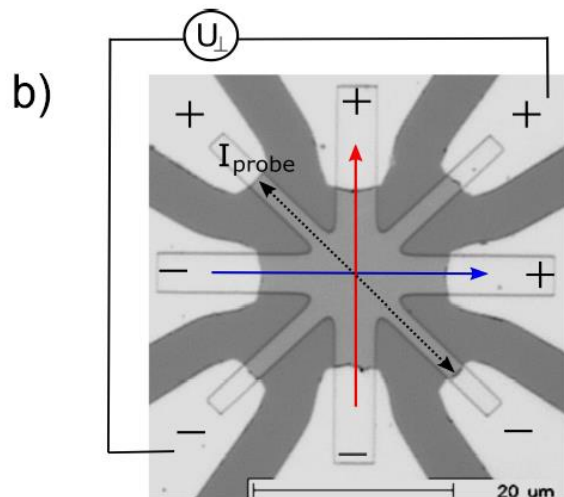
Electrical switching of MnN



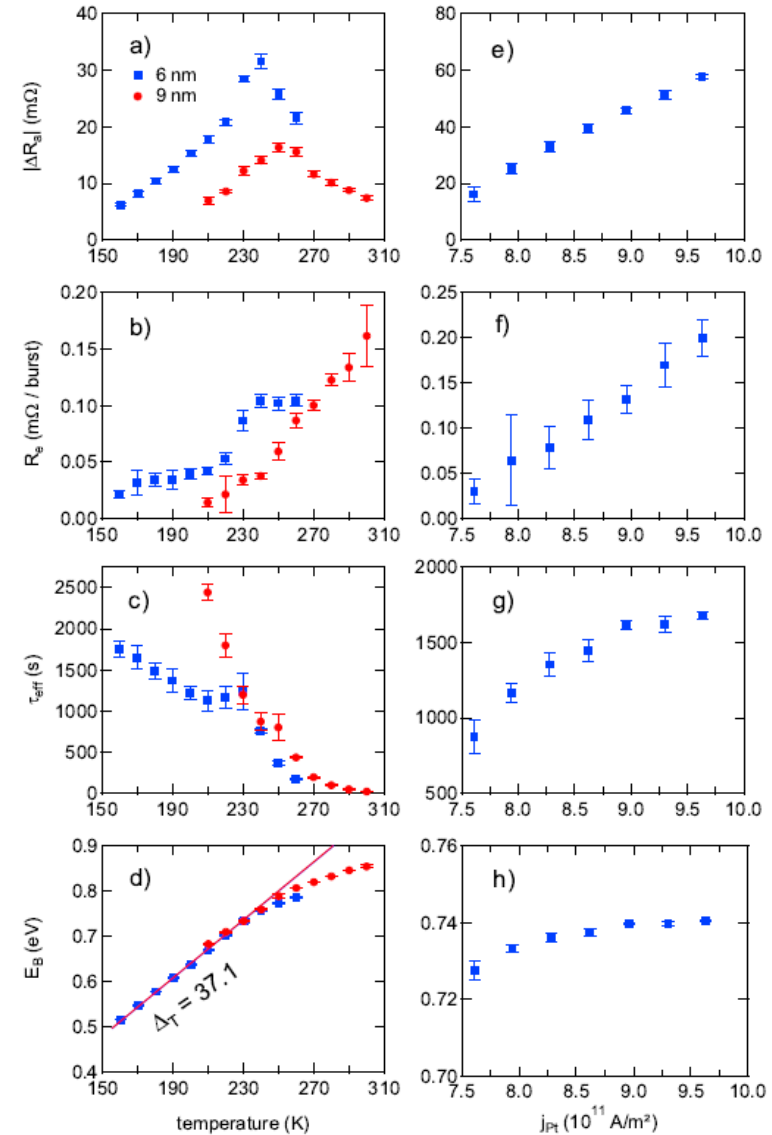
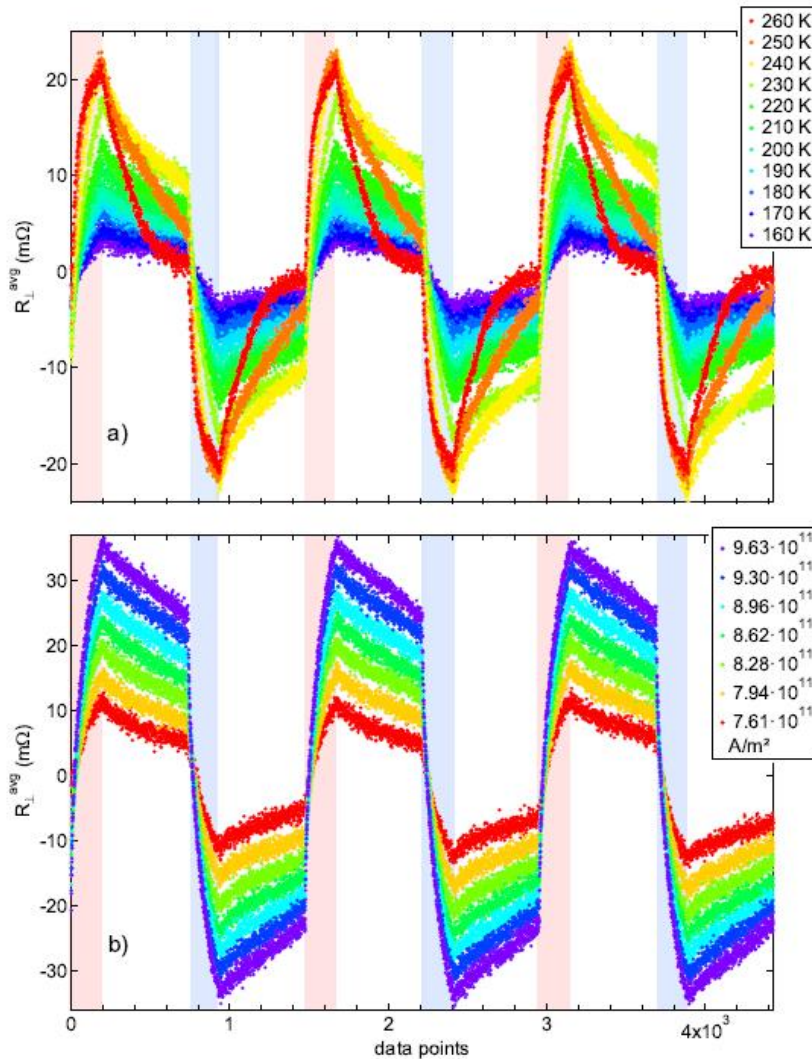
← $\rho \approx 25 \mu\Omega\text{cm}$

← $\rho \approx 200 \mu\Omega\text{cm}$

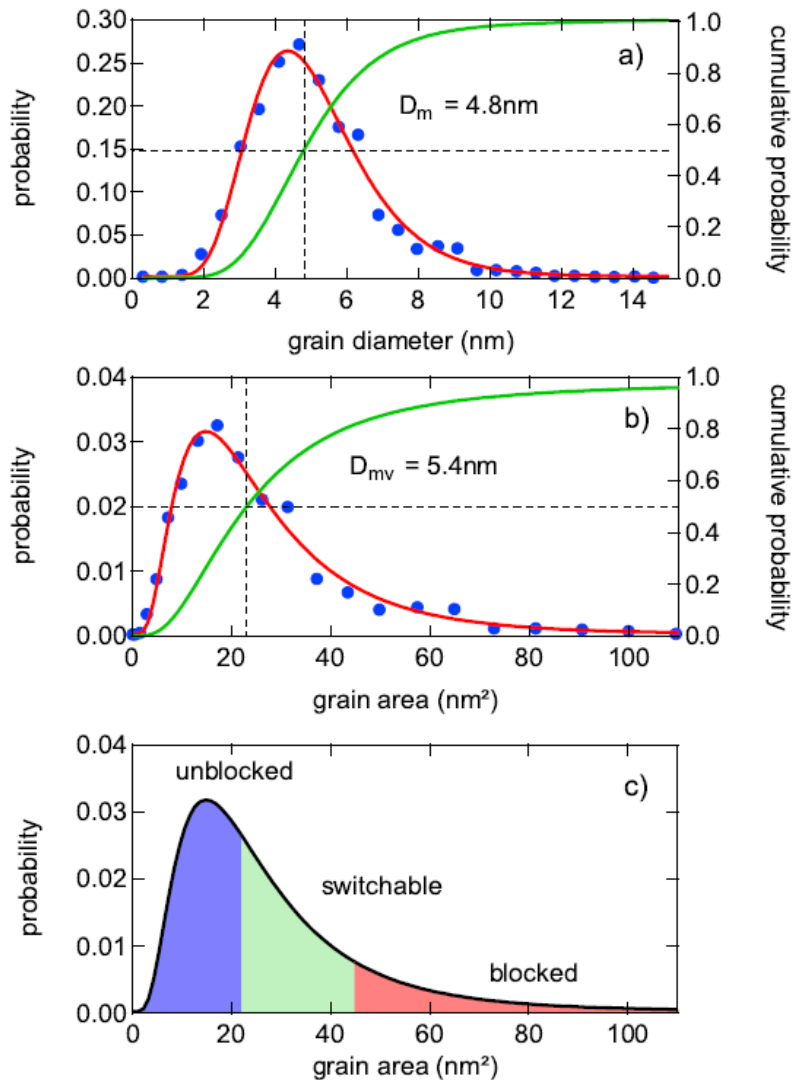
← $\rho \approx 180 \mu\Omega\text{cm}$



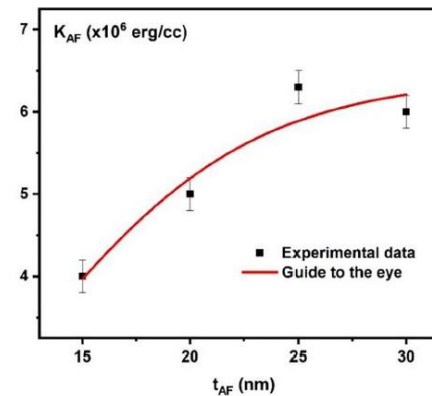
Electrical switching of MnN: Parameters



Grain size analysis

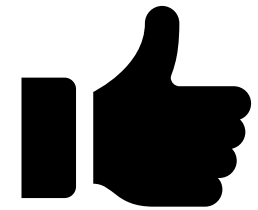
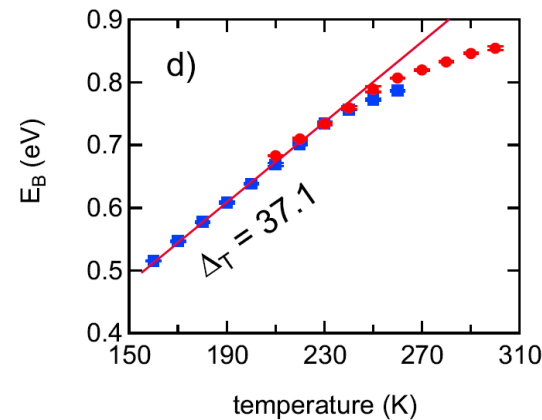


Anisotropy analysis via "York protocol":



$$\langle E_B \rangle \approx 0.5 \text{ eV} @ 9 \text{ nm}$$

Energy barrier from switching and relaxation:



Ohmic contributions to the electrical read-out

UNPUBLISHED

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